Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination TANAKA ET AL.	
10/542,171		
Examiner	Art Unit	
Karie O'Neill Apicella	1726	

	CEAD	CHED			
SEARCHED					
Class	Subclass	Date	Examiner		
429	428-433	1/19/2011	KOA		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examine
US PG/PUB keyword text search (see attached)		1/19/2011	коа

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted with Dah-wei Yuan Re: means language and configured to language	1/19/2011	КОА		
Updated search in EAST	1/19/2011	коа		
Inventor search in eDAN	1/19/2011	КОА		